



PTO/SB/08A (10-01)

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				Application Number	09/957,443
				Filing Date	September 18, 2001
				First Named Inventor	Jason Zweiback
				Art Unit	2872
				Examiner Name	J. Pritchett
Sheet	1	of	1	Attorney Docket Number	64626/P001CP1/10302976

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)	MM-DD-YYYY		
<i>None</i>					

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY		T <sup>6</sup>
<i>None</i>					

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
					T <sup>2</sup>
<i>JP</i>	CA	Albert, J. et al., "Minimization of Phase Error in Long Fiber Bragg Grating Phase Masks made Using Electron Beam Lithography," IEEE Photonics Technology Letters, IEEE Inc., New York, US, October 1, 1996, vol. 8, no. 10, pp. 1334-1336			
<i>JP</i>	CB	Tiberio, R.C. et al., "Fabrication of electron beam generated, chirped, phase mask (1070.11-1070.66nm) for fiber Bragg grating dispersion compensator," Journal of Vacuum Science and Technology: Part B, November 1998, vol. 16, no. 6, pp. 3237-3240			
<i>JP</i>	CC	Chakarian, V. et al., "System architecture choices for an advanced mask writer (100-130 nm)," Proceedings of the SPIE, September 1999, vol. 3873, pp. 1-15			
<i>JP</i>	CD	Morgante, C.G., et al., "The ALTA 3700: Extending the Application Space of the ALTA 3500 Laser Reticle Writer," Proceedings of the SPIE, April 2000, vol. 4066, pp. 1-11			
<i>JP</i>	CE	Rishton S.A. et al., "Raster shaped beam pattern generation," Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, November 1999, vol. 17, no. 6, pp. 2927-2931			
<i>JP</i>	CF	Pfeiffer H.C., et al., "EL-4, A New Generation Electron-Beam Lithography System," Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, November 1, 1993, vol. 11, no. 6, pp. 2332-2341			
<i>JP</i>	CG	Hill, K.O., et al., "Fiber Bragg Grating Technology Fundamentals and Overview," Journal of Lightwave Technology, August 1997, vol. 15, no. 8, pp. 1263-1276			
<i>JP</i>	CH	Ericksson, U. et al., "Design of Fiber Gratings For Total Dispersion Compensation," Optics Letters, Optical Society of America, Washington, US, July 15, 1994, vol. 19, no. 14, pp. 1028-1030			
<i>JP</i>	CI	Communication Relating to the Results of the Partial International Search, PCT/US01/29178, mailed August 20, 2003			

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Examiner Signature	<i>J. Pritchett</i>	Date Considered	<i>09/04</i>
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